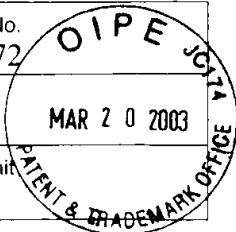


Substitute Form PTO-1449 (Modified)		U.S. Department of Commerce Patent and Trademark Office	Attorney's Docket No. 12732-038001	Application No. 09/852,672
Information Disclosure Statement by Applicant (Use several sheets if necessary) (37 CFR §1.98(b))		Applicant Hideomi Suzawa et al.		
		Filing Date May 11, 2001	Group Art Unit 2812	



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Examiner Signature	Date Considered
EXAMINER: Initial if citation considered. Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.	